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Effect of heat treatment on the structure of L-Ta₂O₅: a study by XRPD and HRTEM methods

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Abstract

The effect of heat treatment on the structure of L-Ta₂O₅ has been studied by X-ray powder diffraction and high-resolution transmission electron microscopy, complemented by density measurements. Two stable low-temperature forms of L-Ta₂O₅ were found: one below about 1000°C with a b^* multiplicity of $m \approx 13.5$ and the other at 1350°C with m = 11. The former modification was disordered, containing defects and twins, while the latter seemed to be more ordered. At intermediate temperatures, ordered and disordered mixtures of L-Ta₂O₅ slabs with m values in the range m = 11-14 were seen. A new model of a structure of L-Ta₂O₅ (m = 11) is proposed. The model can be described as an ordered intergrowth of slabs of α -U₃O₈ and β -U₃O₈ types. The α -U₃O₈ slabs are wider and contain somewhat larger three-sided tunnels that appear to be more suitable for interstitial Ta atoms than the β -U₃O₈ slabs. The density measurements confirm that additional Ta atoms are present in the structure.

Keywords: L-Ta₂O₅; Structure; Multiplicity; X-ray diffraction; HRTEM; Density; Disorder; Intergrowth structure; α-U₃O₈; β-U₃O₈

1. Introduction

The low-temperature variety of tantalum pentoxide, L-Ta₂O₅, exhibits a sluggishly reversible phase transition to a high-temperature modification at about 1360°C. It is therefore difficult to grow single crystals of the low-temperature form by conventional hightemperature techniques [1–4]. The X-ray powder pattern of L-Ta₂O₅ contains strong subcell lines and a number of weak extra lines. Lehovec showed [5] that the stronger lines in the X-ray pattern from an amorphous Ta₂O₅ sample annealed for 8 h at 1100°C could be indexed by using a unit cell with a = 6.20, b = 3.66 and c = 3.89 Å. From cited density values ($\rho \approx 8.02 - 8.27 \text{ g/cm}^3$) Lehovec concluded that the subcell contained one formula unit of Ta₂O₅. Compiling orthorhombic unit-cell dimensions proposed by various authors and comparing them with those of the subcell above, he noted the occurrence of unit cells with 2-, 12- and 19-fold increased b-axis. The diversity of published density values of L-Ta₂O₅, 8.18–8.41 g/cm³, is pointed out in Ref. [6]. In order to account for the extra lines, Frevel

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and Rinn [7] and Terao [8] had to use monoclinic unit cells. The density of L-Ta₂O₅ according to Terao is 8.90 ± 0.01 g/cm³. Moser [9] tried to classify L-Ta₂O₅ modifications by noting the position of one characteristic line, the so-called C line, occurring at a 2θ value of about 26° (CuK α radiation). The position of this reflection has turned out to be strongly dependent on sample preparation, thermal treatment and impurity content.

Difficulties in obtaining single crystals of L-Ta₂O₅ necessitated attempts to introduce certain amounts of other oxides in order to stabilize the L-Ta₂O₅ structure. The oxides added contained three-, four-, and six-valent cations. In particular, phases in the system Ta₂WO₈–Ta₂O₅ have been studied [10–19], and the L-Ta₂O₅-related crystal structures of Ta₂₂W₄O₆₇, Ta₃₀W₂O₈₁ and Ta₃₈WO₉₈ determined from X-ray single-crystal data [14–16]. Very small single-crystals of L-Ta₂O₅ itself could eventually be prepared and a structure have multiplicities m = 13, 8, 19, and 11, where $m = b_0^*/b^*$ and b_0^* corresponds to the lattice cell dimension given by Lehovec [5].

A building-block scheme was developed, based on Andresen's structure for U_3O_8 [21], consisting of edge-

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sharing pentagonal bipyramids with octahedra between the chains, whereby an ideal structure could be predicted for this type of compound. The oxygen:metal ratio of this structure (2.667) can be reduced to a certain extent by "folding" of the straight chains. Further reduction of the ratio is obtained by introducing oxygen vacancies in so-called distortion planes. Fig. 1a shows an idealized crystal structure of L-Ta₂O₅ (m = 11), suggested by Stephenson and Roth [20], that contains 22 metal and 58 oxygen atoms. The real structure, according to these



Fig. 1. (a) The idealized crystal structure of L-Ta₂O₅ (m = 11) given in Ref. [20]. It is a β -U₃O₈(subcell)-type structure twinned at (010) and (020) with the actual composition Ta₂O₅. A further reduction of the O:Ta ratio is accomplished through oxygen vacancies in the metal plane. (b) The crystal structure of Ta₂₂W₄O₆₇ composed of β -U₃O₈ (subcell)-type elements of two different widths twinned at (010). Apical oxygen vacancies are assumed to satisfy the stoichiometry. (c) The crystal structure of Ta₇₄W₆O₂₀₃ composed of α -U₃O₈- and β -U₃O₈ (subcell)-type structures. Apical oxygen vacancies are assumed to satisfy the stoichiometry.

authors, has oxygen vacancies in the metal plane, thus reducing the number of oxygens to 55 per unit cell.

For pure Ta₂O₅ the conclusion has been reached [3,10] that there exist two low-temperature polymorphic phases. In as-received Ta₂O₅ and below about 1000°C a structure with m = 14 occurs, and at higher temperatures ($\approx 1350^{\circ}$ C) one with m = 11. At intermediate temperatures ordered or partially ordered mixtures of the two phases occur in equilibrium with each other [3]. The former phase, with 14 subcell units, has also been observed in as-received Ta₂O₅ by high-resolution transmission electron microscopy (HRTEM) [22]. A single-crystal X-ray structure determination of Ta₂O₅ with m = 12, prepared by a transport reaction at about 800°C, has also been reported [23].

In 1992, Schmid et al. published a study of the L-Ta₂O₅-Ta₂₂W₄O₆₇ system using X-ray powder diffraction and transmission electron microscopy techniques [24]. They concluded that this range could be looked upon as an incommensurately modulated solid solution $(1-x)Ta_2O_5 \cdot xWO_3$, $0 \le x \le 0.267$, with a linearly composition-dependent primary modulation wave vector $\mathbf{q} = q \cdot \mathbf{b}^*$. The corresponding parent structure is supposed to be a slightly orthorhombically distorted, oxygen-deficient α -UO₃-type structure with $a \approx 6.20$, $b \approx 3.66$ and $c \approx 3.89$ A, cf. Ref. [5]. For pure L-Ta₂O₅ heated at 1350°C the authors found q = 0.635, as compared to the theoretical value 7/11 or 0.6363... for a commensurate phase. The structures of Ta₂₂W₄O₆₇ (x = 0.267) and Ta₇₄W₆O₂₀₃ (x = 0.140), with 13- and 8-fold subcell units, respectively, have been refined as composite modulated structures from single-crystal studies with synchrotron radiation [25,26]. These structures are shown in Figs. 1b and c. Some apical oxygen vacancies are assumed to satisfy the stoichiometry. A structure of an L-Ta₂O₅ type phase in the $TiO_2-Ta_2O_5$ system, deduced from HRTEM images, has been described [27] as an ordered intergrowth of α -U₃O₈ and β -U₃O₈ structure types. Some of the images indicated presence of interstitial metal atoms. A relation between q and the multiplicity m based on the so-called C-line [9] is given in Ref. [28].

We may conclude that reported multiplicities of L- Ta_2O_5 (m = 11, 12 and 14) appear to vary with the synthesis, especially the annealing of the oxide. We also note a certain spread in the observed densities, as shown above and elsewhere in the literature. This information together with the observation that interstitial metal atoms may occur in the L- Ta_2O_5 type phase in the $TiO_2-Ta_2O_5$ system gave us the impetus to investigate L- Ta_2O_5 with a well-known thermal pre-history. Thus samples of L- Ta_2O_5 , as received and heated at various temperatures for various periods of time, were investigated by X-ray powder diffraction and HRTEM techniques complemented by density measurements.

2. Experimental

The Ta₂O₅ powder used in this study was obtained from Strem Chemicals. This reagent is reported as containing 99.9% tantalum(V) oxide. Batches of 10-12 g were heated for various lengths of time in a platinum crucible as listed in Table 1. The samples were removed from the furnace and allowed to cool in the crucible. Smaller amounts of samples, however, were contained in unsealed platinum tubes and guenched from the actual calcination temperature as shown in Table 1. The purity of the starting material (sample E1) and the sample E8.23 (annealed at 1340°C for 588 h) was investigated by energy-dispersive X-ray spectroscopy in a JEOL 820 scanning electron microscope (SEM) equipped with a LINK system. The EDS spectra showed only peaks from tantalum. All samples were investigated by X-ray powder diffraction, using a Guinier-Hägg focusing camera with strictly monochromatized $CuK\alpha_1$ radiation and with LaB₆ as internal θ standard (JCPDS-ICDD 34-427, a = 4.15690 Å). The powder photographs were evaluated with an automatic scanner system, and the unit-cell parameters were refined by least-squares techniques.

Density measurements, using helium displacement technique, were made in AccuPyc 1330 standard 10, 1 and 0.1 cm³ Pycnometers from Micromeritics on batches of about 10, 2 and 0.2 g, respectively of Ta_2O_5 . The instruments were checked by determining the densities of dried and ground NaCl, KCl and Pb(NO₃)₂. The densities obtained were found to be 1–2% lower than theoretical.

Electron-microscope specimens were prepared by crushing a small amount of the Ta_2O_5 sample under *n*butanol in an agate mortar. A drop of the resultant suspension was allowed to dry on a copper grid coated with a holey carbon film. The electron microscopy studies were made on 10–15 fragments from each of the

Table 1 Some experimental and derived results from L-Ta₂O₅

preparations in Table 1 (E1–E8.23). A large number of selected-area electron diffraction (ED) patterns were taken in different [h0l] orientations in the JEOL 2000FX-II transmission electron microscope, operated at 200 kV, which was equipped with a double-tilt, sideentry goniometer stage with tilt angles of $\pm 45^{\circ}$. The HRTEM studies of thin crystals were made in the TEMmicroscope, JEOL JEM-3010 (double-tilt $\pm 10-20^{\circ}$, sideentry goniometer stage) operated at 300 kV. Crystallographic image processing by the computer program system CRISP [29] was applied to a couple of HRTEM images taken of crystallites from the sample E8.23 in order to obtain more accurate tantalum atom positions. The structure models are produced with ATOMS by Shape Software.

3. Results

3.1. X-ray powder diffraction and density measurements

The strong reflections in the Guinier photographs were indexed using the orthorhombic parent unit cell with $a \approx 6.20$, $b \approx 3.66$ and $c \approx 3.89$ Å suggested by Lehovec [5]. The four-index notation

$$\mathbf{d}_{h\,k\,l\,n}^* = h\mathbf{a}^* + k\mathbf{b}_0^* + l\mathbf{c}^* + n\mathbf{q}$$

used by Schmid et al. [24] was also used in the present study to index all the reflections. Here \mathbf{a}^* , \mathbf{b}_0^* and \mathbf{c}^* correspond to the reciprocal lattice cell dimensions of the parent structure, and $\mathbf{q} = q \cdot \mathbf{b}_0^*$ is a modulation wave vector. The data were subjected to a least-squares refinement out to about $2\theta = 75^\circ$ for CuK α_1 . The results are shown in Figs. 2a–e. The length of the *a*axis decreases with increasing temperature of preparation (the 1350°C sample is an exception which may be due to the vicinity of the transition temperature to H-Ta₂O₅). The b_0 - and *c*-axis, on the other hand, are

Sample	Heat treatment		$V_{\rm sub}$ (Å ³)	$d_{\rm obs}$	$Z_{ m sub}$	q	m = 1/(2 - 3q)	$m = b_0^*/s^*$ from ED	Remarks
	Temp. (°C)	Time (h)							
E1		_	88.43(5)	8.65(2)	1.042(3)	0.6411(5)	13.0(3)	13.2	As received
E2	550	100	88.60(7)	8.64(1)	1.043(2)	0.6420(8)	13.5(5)	13.2	
E3	700	100	88.42(5)	8.62(1)	1.039(2)	0.6421(6)	13.6(4)	13.0	
E4	850	72	88.44(5)	8.61(1)	1.038(2)	0.6418(6)	13.4(4)	13.5	
E5	1000	72	88.42(6)	8.68(1)	1.046(2)	0.6417(5)	13.4(3)	13.5	
E6	1150	50	88.38(5)	8.72(2)	1.050(3)	0.6401(5)	12.5(3)	12.8	
E6.2	1150	96	88.41(6)	8.72(2)	1.051(4)	0.6402(5)	12.6(3)	13.1	From E6
E8	1300	24	88.38(4)	8.75(1)	1.054(2)	0.6402(3)	12.6(2)	12.2	
E8.2	1300	96	88.33(4)	8.75(1)	1.053(2)	0.6398(4)	12.4(2)	12.3	From E8
E8.21	550	160	88.37(4)	8.76(1)	1.055(2)	0.6396(3)	12.3(2)	12.4	From E8.2 ^a
E8.22	1350	45	88.34(4)	8.76(1)	1.052(2)	0.6369(4)	11.2(2)	11.0	From E8.2 ^a
E8.23	1340	588	88.35(4)	8.79(1)	1.058(2)	0.6370(3)	11.2(1)	10.9	From E8.2 ^a

^aIn unsealed Pt-tubes and quenched from indicated temperature.



Fig. 2. Plots of data versus preparation temperature for L-Ta₂O₅. (a)–(d) Refined unit-cell dimensions, (e) q values obtained from refined XRPDdata, (f) observed density values, d_{obs} , and (g) multiplicity values m = 1/(2 - 3q).

fairly constant. The subcell volumes and the q values decrease with increasing temperature of preparation (Figs. 2d and e). The density d_{obs} (Fig. 2f) first shows a slight decrease and then an increase. The multiplicity m, related to q as m = 1/(2 - 3q) [28] shows a decrease with increasing temperature of preparation (Fig. 2g). Some further details of observed subcell volumes V_{sub} , densities d_{obs} and calculated numbers of formula units of Ta₂O₅, Z_{sub} , as well as q and m values are given in Table 1. Observed and calculated 2θ values for one of the samples (E8.2) are given in Table 2.

3.2. Electron microscopy studies

Electron microscopy studies of the starting material (E1) showed that the as-received Ta_2O_5 powder consisted to a large part of amorphous and badly crystallized fragments. The ED patterns of the latter crystallites showed severe streaking of the subcell reflections along b^* , and the multiplicity value as

shown below could only be calculated from two of the recorded patterns. The amorphous fragments, on the other hand, seemed to crystallize when heated in the electron beam. The diffuse halos observed in the ED pattern from one fragment seemed to change into diffuse rings after a few minutes' exposure to the beam. Our results are similar to those previously reported on the crystallization of thin amorphous tantalum oxide films [30,31].

The ED patterns taken from well-ordered crystallites in the [001], [10–1] and [102] directions contained information about the multiplicity. The pattern in Fig. 3a ([001] zone) shows a pseudo-hexagonal arrangement of strong reflections that originate from the orthorhombic L-Ta₂O₅ subcell suggested by Lehovec [5]. In the three ED patterns (Figs. 3a–c) there are rows of superstructure spots, which are grouped in clusters around the subcell reflections and run parallel to b^* . This is even better seen in Fig. 3d, which shows an enlarged part of the [-1k0] line in Fig. 3a. By measuring the Table 2

Indexed X-ray powder pattern of L-Ta₂O₅ heated at 1300°C for 96 h. A four-index notation $(h, k, l, n) = h\mathbf{a}^* + k\mathbf{b}_0^* + l\mathbf{c}^* + n\mathbf{q}$ has been used, where $\mathbf{a}^*, \mathbf{b}_0^*$ and \mathbf{c}^* are the cell vectors of a reciprocal lattice of a substructure of Lehovec-type with $a = 6.1862(7), b_0 = 3.6674(4)$ and c = 3.8932(5) Å $(\mathbf{q} = q\mathbf{b}_0^* \text{ with } q = 0.6396(3))$

$2\theta_{\rm obs}$	$I_{\rm obs}$	$d_{\rm obs}$	h	k	l	п	$\varDelta(2\theta)$
16.769	2.32	5.283	1	1	0	-1	0.019
17.465	0.92	5.074	0	2	0	-2	0.059
22.819	79.44	3.894	0	0	1	0	0.000
26.552	6.96	3.354	1	1	0	-3	0.001
28.245	100.00	3.157	1	1	0	0	-0.015
28.459	7.68	3.134	1	1	1	-1	0.017
28.843	64.82	3.093	2	0	0	0	0.019
			0	2	1	-2	-0.006
30.027	2.34	2.974	1	3	0	-3	0.014
31.184	1.73	2.866	0	0	0	2	0.012
32.864	2.81	2.723	2	0	0	-1	0.006
33.884	5.26	2.643	2	2	0	$^{-2}$	0.011
35.292	6.87	2.541	1	1	1	-3	0.009
36.631	82.29	2.451	1	1	1	0	0.004
37.099	54.57	2.421	2	0	1	0	0.023
			2	2	1	-3	-0.032
38.040	4.23	2.364	1	3	1	-3	0.006
40.391	1.03	2.231	2	0	1	-1	0.009
42.967	2.25	2.103	1	1	0	1	0.009
			2	0	0	2	-0.001
44.431	4.33	2.037	3	1	0	-2	0.022
44.548	1.84	2.032	2	2	0	-1	0.014
44.797	5.10	2.022	3	1	0	-1	0.015
44.949	3.05	2.015	1	3	0	-2	0.009
45.228	2.07	2.003	3	3	0	-4	-0.019
46.627	29.95	1.946	0	0	2	0	0.013
			0	2	2	-3	-0.033
49.194	4.67	1.851	2	0	1	2	-0.003
49.676	34.76	1.834	0	2	0	0	0.000
50.529	5.68	1.805	3	1	1	-2	0.030
50.730	22.71	1.798	3	1	0	0	0.003
50.990	2.09	1.790	1	3	1	$^{-2}$	0.005
51.278	1.60	1.780	3	3	1	-4	0.017
51.822	7.19	1.763	3	3	0	-3	0.001
54.468	2.90	1.683	1	1	2	-3	0.020
55.390	79.62	1.657	0	2	1	0	0.059
			1	1	2	0	-0.019
55.759	22.06	1.647	2	0	2	0	0.024
			2	2	2	-3	-0.017
56.316	22.54	1.632	3	1	1	0	0.009
57.333	6.74	1.606	3	3	1	-3	0.006
58.442	16.81	1.578	2	2	0	0	-0.009
58.877	1.80	1.567	2	2	2	-2	0.021
59.302	1.71	1.557	1	1	0	2	0.013
59.745	8.11	1.547	4	0	0	0	0.038
			4	2	0	-3	0.000

distance b_0^* of the subcell and the distance s^* between two adjacent spots in a cluster (see Fig. 3d), the multiplicity could be calculated to be $m = b_0^*/s^*$. The average multiplicity value was calculated from a number of ED patterns of each sample. Some of the recorded patterns seemed to be commensurate, while others were incommensurate. The results in Table 1 show that the average *m* values obtained from the ED studies of the preparations are in agreement with those calculated from the XRPD data. The multiplicity decreases from m = 13.5 to m = 11 when the temperature is increased from 1000°C to 1350°C.

A large number of the ED patterns taken of thin crystallites from the low-temperature samples (E1–E6) were of the type shown in Fig. 4a. Diffuse streaking and weak superlattice reflections along the $\langle 100 \rangle$ directions of the pseudo-hexagonal subcell suggest frequent twinning of the structure. The corresponding HRTEM image (Fig. 4b), taken of a rather thick crystallite from the E2 sample, confirms that the crystal is disordered



Fig. 3. Typical ED patterns taken from ordered crystallites aligned along: (a) [001], (b) [10–1], (c) [102], (d) an enlarged part of an array of -1 k 0 reflections from (a). The multiplicity $(m = b_0^*/s^*)$ is calculated from the observed reflections.

and composed of three parts in twin orientations, marked A, B and C. The local average multiplicities calculated from parts A, B and C are 12.3, 12.7 and 12.3, respectively. These values are in fairly good agreement with the multiplicity m = 13.1 calculated from the corresponding ED pattern. The latter value is obtained from a larger part of the fragment, and the difference in m values might to some extent reflect the uncertainty in



Fig. 4. (a) ED pattern taken of a crystallite from the E2 preparation ([001] zone). Streaking and superlattice reflections in twin orientations can be seen. (b) The corresponding HREM image shows three twin domains, marked A, B and C. The distance between two neighboring arrows to the left corresponds to the width of the L-Ta₂O₅ slab, from which the *m* value can be calculated.

the measurements. The arrows to the left in Fig. 4b show that the widths of the L-Ta₂O₅ slabs vary slightly. The dominating slab widths seem to correspond to m = 12 and 13, however. Each part of the crystallite can thus be considered as built up mainly by disordered intergrowth of L-Ta₂O₅ slabs with multiplicities of m = 12 and 13.

The micrograph in Fig. 5 is taken in [001] projection from another L-Ta₂O₅ fragment of the E2 preparation. The *m* value was found to be ≈ 13.5 from the corresponding ED pattern. A contrast modulation with dark and bright bands perpendicular to *b* can be seen in the image. The distance between two neighboring dark bands illustrates the thickness of the corresponding L-Ta₂O₅ slab. By measuring the distances, the local multiplicity values were calculated. In the left part of the image, A, and also in the part marked B, the distance between the bands varies within the range *m* = 12.6-13.5. In the middle of the image there is a small region where the two parts seem to overlap. Here the



Fig. 5. HRTEM image of a crystallite from preparation E2 projected along [001]. Dark bands marked by arrows can be seen at A and B. The distance between neighboring arrows corresponds to the width of the L-Ta₂O₅ slab. The local *m* values were found to be in the range 12.6–13.5. A partly crystallized region is marked C.

distance between the bands is about half of that in the rest of fragment. It seems likely, however, that the difference in contrast modulation between parts A and B is due to crystal tilt. Another reason might be that the L-Ta₂O₅ structure is just being formed, since the micrograph clearly shows crystallization of L-Ta₂O₅ from an amorphous state. In the right-hand part of the image, C, an amorphous region is linked to a fairly crystalline part, and the L-Ta₂O₅ type structure seems to be forming at the boundary. It is also noteworthy that the distances between the faint diffuse bands (see arrows at C) are about the same as those in the ordered parts of the crystallite. Several ED patterns typical of amorphous structures have been taken of fragments from the E2 sample. However, the number of crystallites with amorphous or twinned structures decreased in the samples, when the preparation temperature and the heating time were increased.

No crystal displaying twinning was seen in the samples (E8-E8.23) heated to 1300°C. The HRTEM examination of these crystallites revealed other defect types, such as cracks and fractures. The defect boundaries were usually fairly parallel to b, but a few fault planes at an angle of $30-60^{\circ}$ to the *b*-axis were also seen. The HRTEM image in Fig. 6 is taken of a defectrich L-Ta₂O₅ crystal from E8.21. The multiplicity of the crystal ($m \approx 12.2$) was calculated from the corresponding ED pattern. The defect region in the image shows that the dark and bright bands of different contrast features are displaced in relation to each other across the diffuse fault boundary. The average multiplicity value ($m \approx 11$) calculated from the top part is slightly less than that $(m \approx 11.9)$ of the bottom region. The difference in width of the L-Ta₂O₅ slabs, and the observed difference in *m* values across the fault indicate that lateral ordering takes place in the $L-Ta_2O_5$ structure by small movements of atoms during the thermal treatment. The results show that the multiplicity value decreases towards m = 11, which apparently represents the stable low-temperature form of L-Ta₂O₅ at 1350°C.



Fig. 6. HRTEM image of a thin crystallite ([001] zone) from the preparation E8.21, showing displacements of the L-Ta₂O₅ slabs across a fault boundary.

Those preparations that had undergone long annealing at high temperatures gave definitely more ordered crystals. The HRTEM image in Fig. 7a is taken of a thin fragment from preparation E8.23. The corresponding ED pattern indicated an ordered modulated structure of multiplicity m = 11. Fig. 7b is obtained by crystallographic image processing of the HRTEM image by the CRISP program [29], and a model of a possible structure based on its contrast features is proposed in Fig. 7c. A structure determination of L-Ta₂O₅ (m = 11) from HRTEM images by crystallographic image processing in combination with a Rietveld X-ray powder diffraction refinement on the subcell will be published.

4. Discussion

The results shown in Fig. 2 and in Table 1 are obtained from as-received Ta₂O₅ and from specimens calcined in air at increasing temperatures, from 550°C up to 1350°C, for indicated periods of time. The densities range from 8.61 (at 850°C) to 8.79 g/cm³ at 1340°C, thus increasing with increasing temperature of treatment. Comparing the densities of samples E8.22 and E8.23, it seems that longer heating times give denser structures. The values are well above those reported in Ref. [5,6] and somewhat below that given in Ref. [8]. It should be noted that the observed densities are higher than the calculated density of 8.31 g/cm³ from a singlecrystal structure determination of L-Ta₂O₅ [20]. It should further be noted that the calculated numbers of formula units, Z_{sub} , for all samples range from 1.038 to 1.058. This will be further commented upon below.

The multiplicities were calculated from q values [28], obtained from indexed X-ray powder diffraction patterns (XRDP), according to the formula m = 1/(2-3q) as shown in Table 1. Multiplicity data from XRDP and the ED study are assumed to give an average value from



Fig. 7. (a) HRTEM image of a L-Ta₂O₅ crystal with m = 11 projected along the 3.9 Å axis. (b) The image processed by the CRISP program. (c) Structure model of L-Ta₂O₅ deduced form the processed image in (b). The interstitial Ta atoms in the three-sided tunnels are not drawn.

the actual sample, and the two sets of data agree in general. Table 1 shows a general decrease with increasing temperature of treatment for temperatures at 1000°C and above, with *m* values ranging from about 13.5 at 1000°C to 11.0 at 1350°C. This is in good agreement with earlier work (3, 10, 12, 13, 18), although the multiplicities given in Ref. [12] apparently have to be halved. It is notable that an L-Ta₂O₅ specimen held at high temperature and then annealed at 550°C preserves the multiplicity and the density acquired at the higher temperature, cf. samples E8 and E8.21 in Table 1, indicating that the annealing temperature is too low to

bring about a noticeable change in the sample. On the other hand, experiments showed treatment of a high-temperature sample (E8) at 900°C for 3 weeks to result in *m* increasing from 12.6 to 13.6. No change in density was observed, however.

It was also found that treatment of E4 (annealed at 850°C) at the slightly higher temperature of 900°C for about three weeks resulted in a density increase from 8.61 to 8.71 g/cm^3 . The multiplicity, however, was not changed. It thus appears that the multiplicity of L-Ta₂O₅ responds to changes in temperature irrespective of earlier heat treatments. It also seems that the observed density depends on the thermal pre-history of the sample in such a way that a density acquired at a high temperature cannot be changed by annealing at a lower temperature for reasonable periods of time. Our results also show that there are two stable lowtemperature modifications of Ta₂O₅, one below $1000^{\circ}C \ (m \approx 13.5)$ and the other at $1350^{\circ}C \ (m = 11)$, thus generally confirming earlier results [3,10,22]. However, electron microscopy studies show that local variations of multiplicity values are abundant, indicating a high degree of disorder in the L-Ta₂O₅ structure.

With the results obtained we may now estimate the number of atoms in L-Ta₂O₅ of a given multiplicity. For an L-Ta₂O₅ specimen heated at 1350°C (E8.22 in Table 1) we find $Z_{sub} = 1.052$, giving a calculated cell content of Ta_{23.144}O_{57.860} or Ta_{23.2}O₅₈ for an 11-fold superstructure. Similarly, we obtain for L-Ta₂O₅ heated at 1000°C (E5 in Table 1) $Z_{sub} = 1.046$ giving Ta_{27.196}O_{67.990} or Ta_{27.2}O₆₈ for a 13-fold superstructure. A 14-fold superstructure gives Ta_{29.29}O_{73.22}, or Ta_{29.6}O₇₄. Density measurements indicate, assuming the occurrence of 11- and 13- (or 14)-fold superstructures without oxygen vacancies, that there are 1.2–1.6 extra, interstitial, Ta atoms per unit cell in these two samples.

In this connection it is interesting to note Lehovec's comments on the structure of L-Ta₂O₅. He assumed a possible "incorporation of foreign ions, particularly cations" into the plane of apical oxygens at z = 1/2 [5]. It is also interesting to note that in their structure determination of L-Ta₂O₅ with m = 11, Stephenson and Roth discussed an ideal model with 58 oxygens in the unit cell [20]. Assuming 22 Ta atoms in the cell they had to introduce oxygen vacancies in so-called distortion planes in the structure, whereby the number of oxygens was reduced to 55. Our density measurements do not contradict an ideal model with 58 oxygen and 22 tantalum atoms per cell, as suggested in Ref. [20], but with additional Ta atoms interstitially inserted to achieve electroneutrality. This is also in line with the findings of Harburn et al. [27].

The new proposed crystal structure of L-Ta₂O₅ with m = 11 in Fig. 7c is in agreement with the conclusions reached above. The model can be described as an

ordered intergrowth of slabs of α -U₃O₈ and β -U₃O₈ type. The α -U₃O₈ slabs are built up entirely from pentagonal TaO₇ bipyramids linked by corner- and edge-sharing so that tunnels with three-sided passages are created. These slabs constitute the major part of the structure. Their composition corresponds to Ta_3O_8 . The β -U₃O₈ slabs, the minor part, consist of pentagonal TaO_7 bipyramids and TaO_6 octahedra in a corner- and edge-sharing arrangement. The passages of the resulting tunnels are narrower than those of α -U₃O₈ type. The width of these slabs is such that the composition corresponds to Ta_2O_5 . The α -U₃O₈ slabs (of Ta_3O_8 stoichiometry) with their somewhat wider tunnels thus appear to be more suitable for interstitial Ta atoms than the slabs of β -U₃O₈ type (with Ta₂O₅ stoichiometry), resulting in tricapped trigonal prismatic coordination, for example as in $K_6Ta_{10.8}O_{30}$ [32]. It is of course still possible that L-Ta₂O₅ contains some oxygen vacancies, but the occurrence might be lower than hitherto thought. In the L-Ta₂O₅-type structures of $Ta_{74}W_6O_{203}$ (Fig. 1b) and $Ta_{22}W_4O_{67}$ (Fig. 1c), on the other hand, the β -U₃O₈ type slabs comprise the major part of the structure. The reason might be that the tungsten atoms prefer octahedral coordination, present in the β -U₃O₈ type slabs [25].

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References

- [1] S. Lagergren, A. Magnéli, Acta Chem. Scand. 6 (1952) 444.
- [2] A. Reisman, F. Holtzberg, M. Berkenblit, M. Berry, J. Am. Chem. Soc. 78 (1956) 4514.

- [3] R.S. Roth, J.L. Waring, J. Res. Natl. Bur. Stand. Sect. A 74 (1970) 485.
- [4] G. Harburn, R.J.D. Tilley, R.P. Williams, Philos. Mag. A 68 (1993) 633.
- [5] K. Lehovec, J. Less-Common Met. 7 (1964) 397.
- [6] A. Reisman, F. Holtzberg, in: A.M. Alper (Ed.), High Temperature Oxides II, Academic Press, New York, London, 1970, p. 217.
- [7] L. Frevel, H. Rinn, Anal. Chem. 27 (1955) 1329.
- [8] N. Terao, J. Appl. Phys. Tokyo 6 (1967) 21.
- [9] R. Moser, Schweiz. Mineral. Petrogr. Mitt. 45 (1965) 35.
- [10] R.S. Roth, J.L. Waring, H.S. Parker, J. Solid State Chem. 2 (1970) 445.
- [11] J.L. Waring, R.S. Roth, J. Res. Natl. Bur. Stand. Sect. A 72 (1968) 175.
- [12] J.M. Williams, R.J.D. Tilley, G. Harburn, R.P. Williams, J. Solid State Chem. 92 (1991) 460.
- [13] R.S. Roth, N.C. Stephenson, in: L. Eyring, M. O'Keefe (Eds.), Chemistry of Extended Defects in Non Metallic Solids, North-Holland, Holland, Amsterdam, 1970, p. 117.
- [14] N.C. Stephenson, R.S. Roth, Acta Crystallogr. B 27 (1971) 1010.
- [15] N.C. Stephenson, R.S. Roth, Acta Crystallogr. B 27 (1971) 1018.
- [16] N.C. Stephenson, R.S. Roth, Acta Crystallogr. B 27 (1971) 1031.
- [17] T. Miyano, K. Kosuge, Eur. J. Solid State Inorg. Chem. 31 (1994) 867.
- [18] T. Miyano, J. Solid State Chem. 126 (1996) 208.
- [19] T. Miyano, Jap. Soc. Electron Microsc. 47 (1998) 47.
- [20] N.C. Stephenson, R.S. Roth, Acta Crystallogr. B 27 (1971) 1037.
- [21] A.F. Andresen, Acta Crystallogr. 11 (1958) 612.
- [22] T.R. Wagner, J. Solid. State Chem. 91 (1991) 189.
- [23] H.-U. Hummel, R. Fackler, P. Remmert, Chem. Ber. 125 (1992) 551.
- [24] S. Schmid, R.L. Withers, J.G. Thompson, J. Solid State Chem. 99 (1992) 226.
- [25] S. Schmid, J.G. Thompson, A.D. Rae, B.D. Butler, R.L. Withers, N. Ishizawa, S. Kishimoto, Acta Crystallogr. B 51 (1995) 698.
- [26] A.D. Rae, S. Schmid, J.G. Thompson, R.L. Withers, N. Ishizawa, Acta Crystallogr. B 51 (1995) 709.
- [27] G. Harburn, R.J.D. Tilley, J.M. Williams, R.P. Williams, J. Hutchison, J. Chem. Soc. Faraday Trans. 88 (1992) 621.
- [28] B.-O. Marinder, J. Solid State Chem. 160 (2001) 62.
- [29] S. Hovmöller, Ultramicroscopy 41 (1992) 121.
- [30] J. Harvey, H. Wilman, Acta Crystallogr. 14 (1961) 1278.
- [31] J. Spyridelis, P. Delavignette, S. Amelinckx, Phys. Status Solidi 19 (1967) 683.
- [32] A.A. Awadalla, B.M. Gatehouse, J. Solid State Chem. 23 (1978) 349.